## Application/Control No. Applicant(s)/Patent Under Reexamination 10/067,309 ITO, HIROSHI Notice of References Cited Art Unit Examiner Page 1 of 1 Edna Wong 1753 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2001/0045974 Shoemaker et al. 347/63 11-2001 Α US-2002/0192572 12-2002 Lau, Simon 430/5 В С US-2003/0000930 01-2003 Hamada, Shiro 219/121.73 US-D US-Ε US-F US-G US-Н USı US-J US-K US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Name Classification Country Code-Number-Kind Code Country MM-YYYY Ν 0 Р Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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